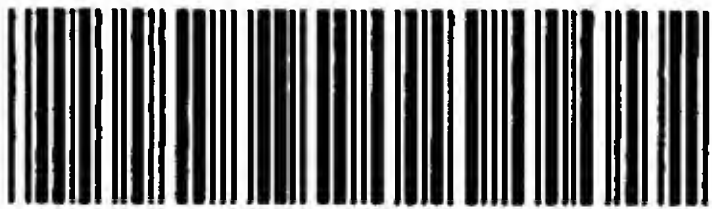


<div>Search Notes</div> 	<div>Application/Control No.</div> <div>10709592</div>	<div>Applicant(s)/Patent Under Reexamination</div> <div>CHENG ET AL.</div>
	<div>Examiner</div> <div>Debelie, Mitiku</div>	<div>Art Unit</div> <div>2621</div>

SEARCHED			
Class	Subclass	Date	Examiner
386	46, 52, 95, 125	8/16/2007	MD
348	207.99, 500, 553, 571	8/16/2007	MD

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner